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U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10063869	05/21/2002	324	75	2858	TRUNG NGUYEN

\*\*APPLICANTS: Araki Chihiro:

\*\*CONTINUING DATA VERIFIED:

none

\*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-161739 05/30/2001

PG-PUB ☐ DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed ☐ yes ☒ no  
35 USC 119 conditions met ☐ yes ☒ no  
Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO

SIMTEK6349

TITLE : Inspection method and inspection apparatus for semiconductor circuit

U.S. DEPT. OF COMM. PAT. & TM. PTO 4161 Rev. 12-94

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
ISSUE FEE			Total Claims	Print Claim for O.G.
Amount Due	Date Paid	Primary Examiner	DRAWING	
<input type="checkbox"/> TERMINAL DISCLAIMER			Sheets Drwg.	Figs. Drwg.
		Application Examiner		
		PREPARED FOR ISSUE	WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.	

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